

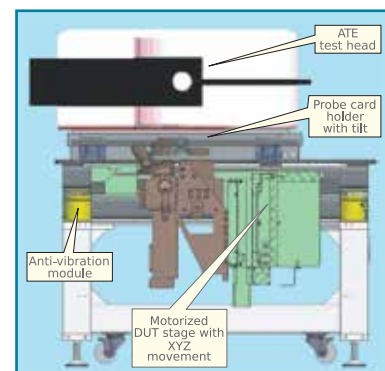
SEMICAPS 4000

INVERTED ANALYTICAL AND TESTER-DOCKED SYSTEM

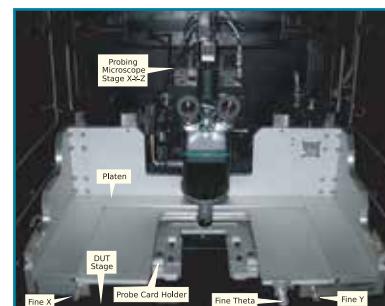


Features

- Analytical or ATE docked configuration
- 300 mm wafer stage including auto-lock compatible with Production Probe Cards and manipulators
- Docks easily to Tester or Probe Station
- High resolution stage with 0.5 μm repeatability
- Centric and Aplanatic Refractive Solid Immersion Lens (RSIL) option
- CAD interface option
- Compatible with thermal management solutions
- Techniques include a combination of :
 - Laser Timing Probe (LTP)
 - Scanning Optical Microscopy (SOM) with best sensitivity
static : TIVA, OBIRCH
dynamic : LADA, SDL
 - Photon Emission Microscopy (PEM) with various options for the InGaAs or Si-CCD camera
 - Thermal Microscopy (THM) with InSb camera



ATE-Docked



300 mm Probe Station

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